

# How accurately are the interaction potentials known in ion scattering spectroscopy?

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## Introduction

- Although elemental identification and compositional information only requires the binary collision model, the ion-surface interaction potential (IP) is a prerequisite for undertaking any detailed structural analysis with ion beam techniques, including CAICISS (coaxial impact collision ion scattering spectroscopy).
- The most frequently used IPs are the Thomas-Fermi-Molière (TFM) and the "Universal" Ziegler-Biersack-Litmark (ZBL) Potential.
- Especially at low energies, these potentials have to be varied to reproduce experimental results. This is typically done by multiplying the screening length by a correction factor,  $C$ .

## CAICISS

- Coaxial impact collision ion scattering spectroscopy [1] offers the chance to probe the structure and composition of surfaces with a high degree of surface specificity.
- Technique has been used to study a range of surface science problems, including real-time growth, surface reconstructions and surface alloy formation.
- Time-of-flight  $\Rightarrow$  composition information from binary collision.
- Shadow cones  $\Rightarrow$  structural information from ion-target interaction.
- Extract intensity vs. polar angle plot for each element.
- Use computer simulations to derive a model for the surface.

## Screened Coulomb Potentials

Thomas Fermi Molière (TFM):

$$\Phi_{TFM}(x) = 0.35 \cdot \exp(-0.3x) + 0.55 \cdot \exp(-1.2x) + 0.1 \cdot \exp(-6x)$$

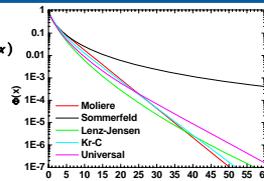
with  $x = r/a$ , where  $a = C_r \cdot a_{TFM}$

$C_r$  ... constant factor, of the order of 0.65 - 1.25 [2]

$$\text{or } C_r = 0.042 \cdot (\sqrt{Z_1} + \sqrt{Z_2}) + 0.57 \text{ [3]}$$

and  $a_{TFM}$  being either  $a_{TFM} = \frac{0.88534 \cdot a_0}{(\sqrt{Z_1} + \sqrt{Z_2})^{0.715}}$

... or  $a_{TFM} = \frac{0.88534 \cdot a_0}{(\sqrt{Z_1} + \sqrt{Z_2})^2}$ .

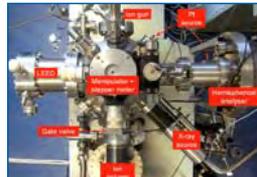
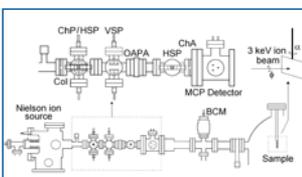


Other Potentials:

- ZBL / "Universal" > Lenz - Jensen
- Sommerfeld > Kr - C

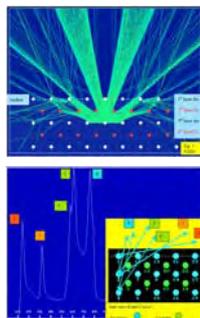
## Experimental Details

- CAICISS, LEED and XPS for chemical and structural information.
- Sputter ion gun, thermal gas cracker and target heating up to 800°C.
- All samples prepared using cycles of Ar<sup>+</sup> bombardment and annealing.
- Use FAN code (see below) to interpret CAICISS data [4].



## FAN Simulation Code [4]

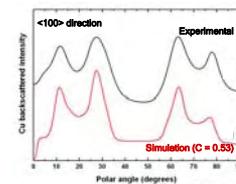
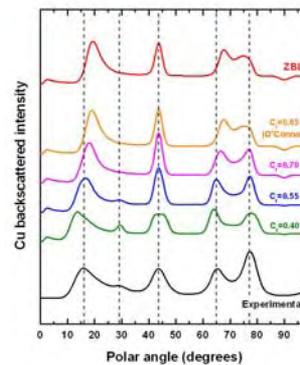
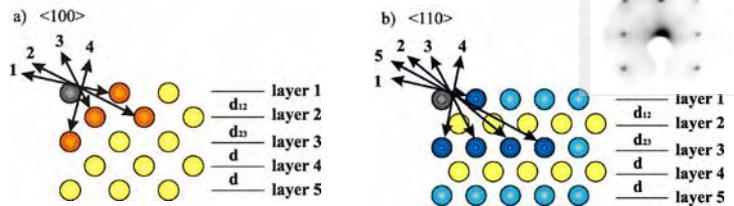
- Enables fast simulations of particle trajectories (ions & neutrals).
- Designed specifically for backscattering techniques.
- Capable of simulating polar and azimuthal crystal rotations.
- Trial structures can incorporate three different atomic species.
- Enables choice of interaction potential (TFM or ZBL) and screening factor.
- Includes temperature and neutralisation effects, as well as off-axis scattering.
- Does not include inelastic energy losses along the trajectory.



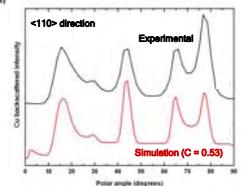
## Results

> Clean Cu(100):  $d_{12} = 1.74 \text{ \AA}$ ,  $d_{23} = 1.83 \text{ \AA}$ ,  $d = 1.807 \text{ \AA}$

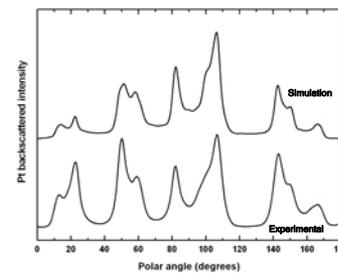
LEED @ 64 eV



Best replication of the experimental data from the Cu(100) surface in both the <100> and <110> directions given by  $C_r = 0.53$ .

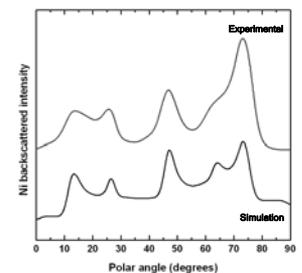


> Clean Pt(111) [5]



> Best fit produced using  $C_r = 0.78$

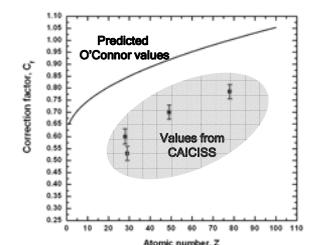
> Ni(110)-(3x1)-O [6]



> Best fit produced using  $C_r = 0.60$

Element	O'Connor C factor [3]	CAICISS C factor
Ni	0.84	$0.60 \pm 0.03$
Cu	0.85	$0.53 \pm 0.03$
In	0.92	$0.70 \pm 0.03$
Pt	1.00	$0.78 \pm 0.03$

> All values derived from experiments using 3 keV He<sup>+</sup>.



## Conclusions

- "Universal" ZBL potential and O'Connor correction to the screening length in the TFM potential are both inadequate in describing CAICISS data recorded using 3 keV He<sup>+</sup> ions.
- Correction factor for Firsov screening length was determined to be lower than predicted by O'Connor for the Cu(100), Pt(111), InN(0001) and Ni(110)-(3x1)-O surfaces.
- ZBL potential underestimates the electron screening at large distances and this leads to incorrect peak positions in the CAICISS polar angle scans.
- To fully understand these results, further work is required at different primary energies (1-5 keV) on more surfaces in order to establish the target mass and primary energy dependencies of the correction factor.

## References

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- [4] H. Niehus, W. Heiland and E. Taglauer, *Surf. Sci. Rep.* **17** (1993) 213.
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